INTEGRATED CIRCUITS



Product specification IC23 Data Handbook 1995 Sep 18



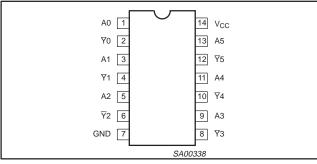
Philips Semiconductors

74ABT04

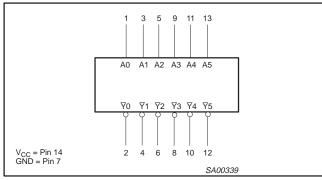
QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS $T_{amb} = 25^{\circ}C;$ GND = 0V	TYPICAL	UNIT
t _{PLH} t _{PHL}	Propagation delay An to Yn	C _L = 50pF; V _{CC} = 5V	2.2 1.6	ns
t _{OSLH} t _{OSHL}	Output to Output skew	vCC = 3 v	0.4	ns
C _{IN}	Input capacitance	$V_I = 0V \text{ or } V_{CC}$	3	pF
I _{CC}	Total supply current	Outputs disabled; $V_{CC} = 5.5V$	50	μΑ

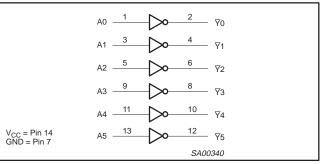
PIN CONFIGURATION



LOGIC SYMBOL



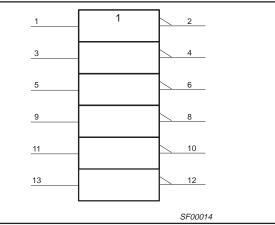
LOGIC DIAGRAM



PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1, 3, 5, 9, 11, 13	An	Data inputs
2, 4, 6, 8, 10, 12	Ϋ́n	Data outputs
7	GND	Ground (0V)
14	V _{CC}	Positive supply voltage

LOGIC SYMBOL (IEEE/IEC)



FUNCTION TABLE

INPUTS	OUTPUT
An	₹n
L	Н
н	L
NOTEO	

NOTES:

H = High voltage level L = Low voltage level

L = LOW VOILage level

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
14-Pin Plastic DIP	-40°C to +85°C	74ABT04 N	74ABT04 N	SOT27-1
14-Pin plastic SO	-40°C to +85°C	74ABT04 D	74ABT04 D	SOT108-1
14-Pin Plastic SSOP Type II	-40°C to +85°C	74ABT04 DB	74ABT04 DB	SOT337-1
14-Pin Plastic TSSOP Type I	-40°C to +85°C	74ABT04 PW	74ABT04PW DH	SOT402-1

ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
I _{IK}	DC input diode current	V ₁ < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
I _{OUT}	DC output current	output in Low state	40	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

 Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

 The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
The input and output upters reliase maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	LIMITS				
STMBOL	TANAMETER	MIN	MAX	UNIT			
V _{CC}	DC supply voltage	4.5	5.5	V			
VI	Input voltage	0	V _{CC}	V			
V _{IH}	High-level input voltage	2.0		V			
V _{IL}	Low-level input voltage		0.8	V			
I _{OH}	High-level output current		-15	mA			
I _{OL}	Low-level output current		20	mA			
Δt/Δv	Input transition rise or fall rate	0	5	ns/V			
T _{amb}	Operating free-air temperature range	-40	+85	°C			

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER TEST CONDITIONS		T _{amb} = +25°C			T _{amb} = −40°C to +85°C		UNIT
				TYP	MAX	MIN	MAX	1
V _{IK}	Input clamp voltage	$V_{CC} = 4.5V; I_{IK} = -18mA$		-0.9	-1.2		-1.2	V
V _{OH}	High-level output voltage	V_{CC} = 4.5V; I_{OH} = -15mA; V_I = V_{IL} or V_{IH}	2.5	2.9		2.5		V
V _{OL}	Low-level output voltage	V_{CC} = 4.5V; I_{OL} = 20mA; V_I = V_{IL} or V_{IH}		0.35	0.5		0.5	V
lı	Input leakage current	V_{CC} = 5.5V; V_I = GND or 5.5V		±0.01	±1.0		±1.0	μΑ
I _{OFF}	Power-off leakage current	V_{CC} = 0.0V; V_{O} or $V_{I} \le 4.5V$		±5.0	±100		±100	μA
I _{CEX}	Output High leakage current	V_{CC} = 5.5V; V_{O} = 5.5V; V_{I} = GND or V_{CC}		5.0	50		50	μΑ
Ι _Ο	Output current ¹	$V_{CC} = 5.5V; V_{O} = 2.5V$	-50	-75	-180	-50	-180	mA
I _{CC}	Quiescent supply current	V_{CC} = 5.5V; V_{I} = GND or V_{CC}		2	50		50	μΑ
ΔI _{CC}	Additional supply current per input pin ²	V_{CC} = 5.5V; One data input at 3.4V, other inputs at V_{CC} or GND		0.25	500		500	μΑ

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

2. This is the increase in supply current for each input at 3.4V.

AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5$ ns; $C_L = 50$ pF, $R_L = 500\Omega$

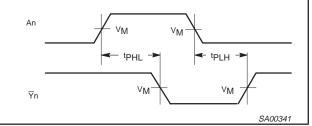
SYMBOL								
	PARAMETER	WAVEFORM	T _{amb} = +25°C V _{CC} = +5.0V			$T_{amb} = -40^{\circ}$ $V_{CC} = +5$	UNIT	
			MIN	ТҮР	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay An to Yn	1	1.0 1.0	2.2 1.6	3.4 2.5	1.0 1.0	4.1 3.0	ns
^t OSHL tOSLH ¹	Output to Output skew An or Bn to $\overline{Y}n$	2		0.4	0.5		0.5	ns

NOTE:

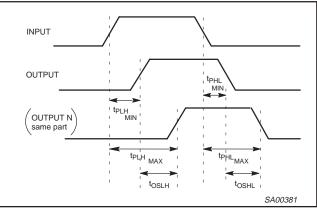
 Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}); parameter guaranteed by design.

AC WAVEFORMS

 $V_{M} = 1.5V, V_{IN} = GND \text{ to } 3.0V$

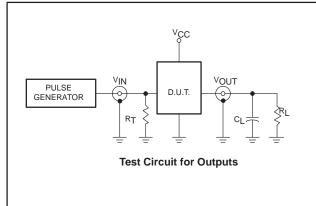


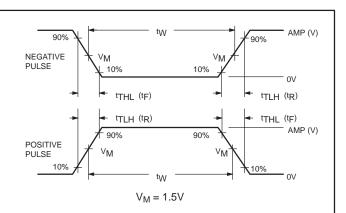
Waveform 1. Propagation delay for inverting outputs



Waveform 2. Common edge skew

TEST CIRCUIT AND WAVEFORMS





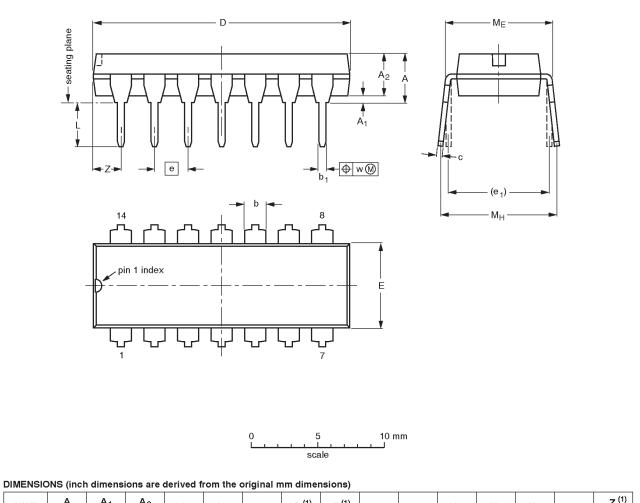
Input Pulse Definition

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
- $\label{eq:RT} R_T = \begin{tabular}{ll} Termination resistance should be equal to Z_{OUT} of pulse generators. \end{tabular}$

FAMILY	IN	PUT PULSE R	EQUIRE	MENTS	
	Amplitude	Rep. Rate	t _W	t _R	t _F
74ABT	3.0V	1MHz	500ns	2.5ns	2.5ns
					SHOODEZ

DIP14: plastic dual in-line package; 14 leads (300 mil)



UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	c	D ⁽¹⁾	E ⁽¹⁾	e	e ₁	L	ME	м _н	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

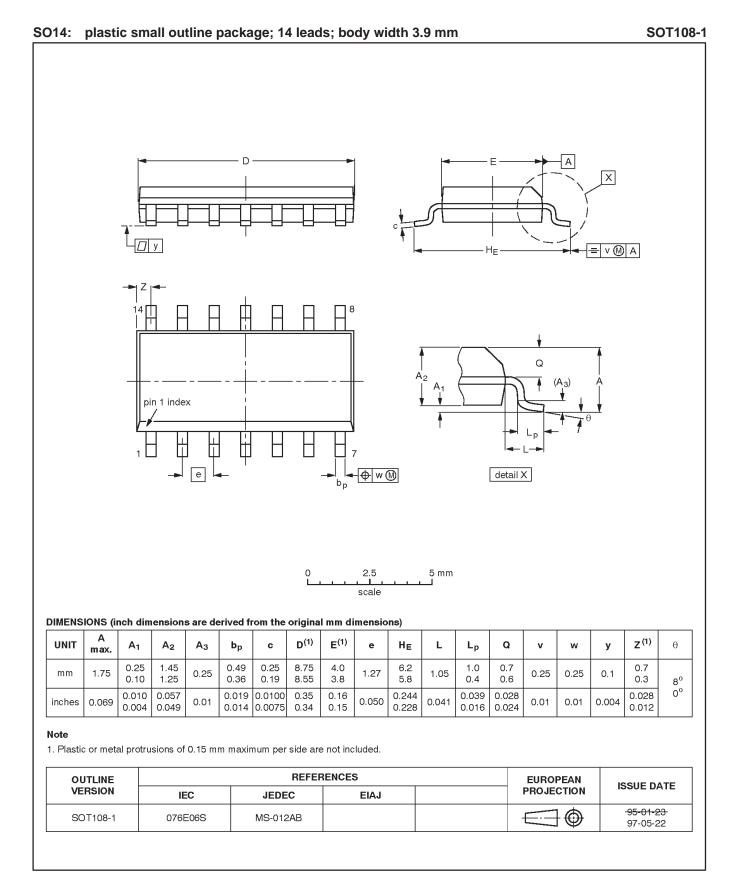
OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
SOT27-1	050G04	MO-001AA			-92-11-17 95-03-11	

Product Specification

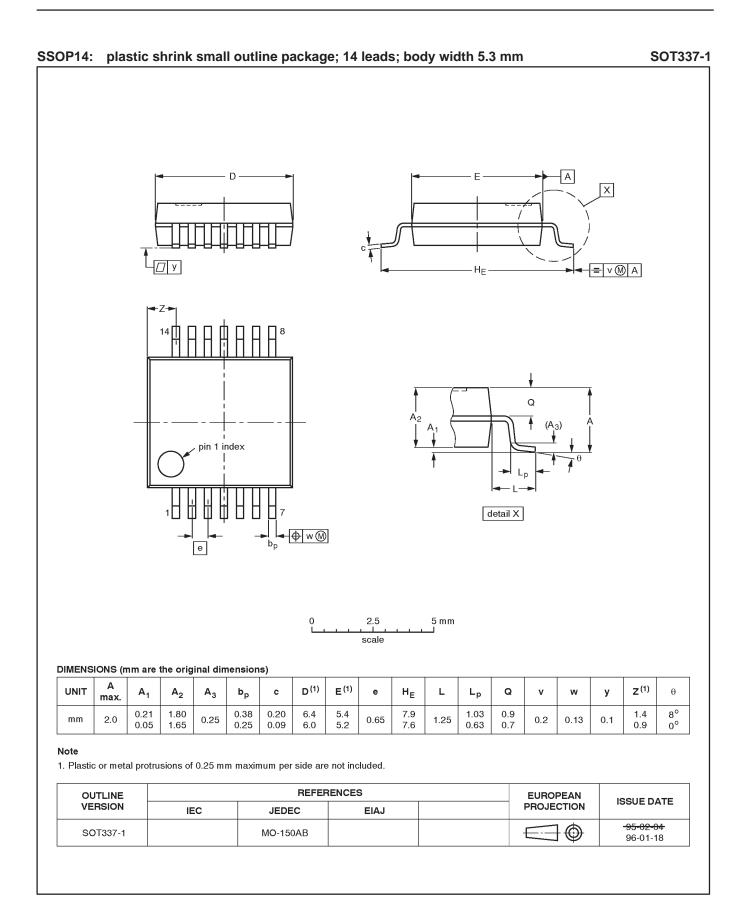
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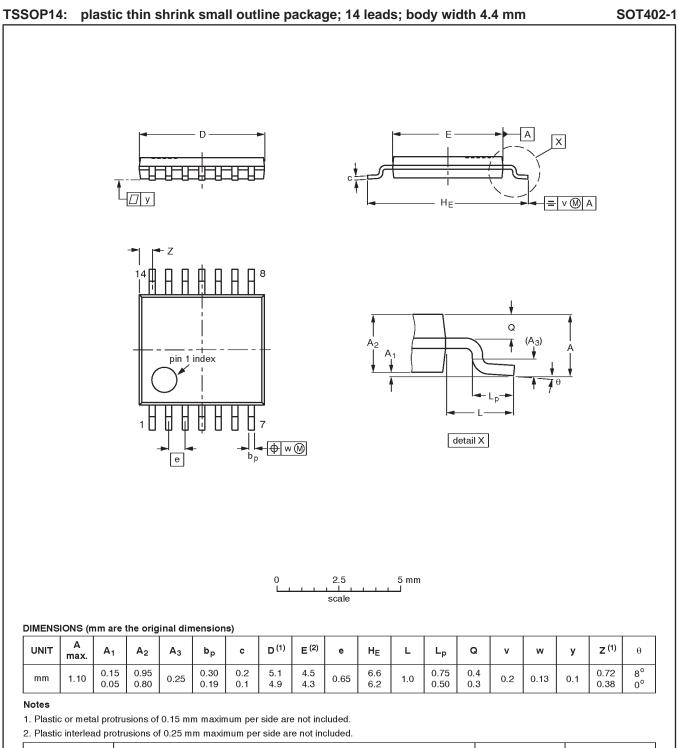
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74ABT04



OUTLINE					EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT402-1		MO-153				-94-07-12 95-04-04	

NOTES

DEFINITIONS		
Data Sheet Identification	Product Status	Definition
Objective Specification	Formative or in Design	This data sheet contains the design target or goal specifications for product development. Specifications may change in any manner without notice.
Preliminary Specification	Preproduction Product	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.
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